


<b>Search Notes</b>  	<b>Application/Control No.</b>  10553624	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHATA ET AL.
	<b>Examiner</b>  CHRISTIAN A HANNON	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	569.1	12/29/2008	CH
181	171,172,157	12/29/2008	CH
379	433.02	12/29/2008	CH
381	388,386,333	12/29/2008	CH

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted E. Urban; see printout	12/29/2008	CH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/CHRISTIAN A HANNON/ Examiner.Art Unit 2618	
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